

# Vortices and Flux Pinning Coated Conductors

D. K. Christen

Oak Ridge National Laboratory, Oak Ridge TN

## INVITED PRESENTATION

MURI-CC-03 Workshop  
Madison, WI  
June 11–13, 2003

"The submitted manuscript has been authored by a contractor of the U.S. Government under contract No. DE-AC05-00OR22725. Accordingly, the U.S. Government retains a nonexclusive, royalty-free license to publish or reproduce the published form of this contribution, or allow others to do so, for U.S. Government purposes."

prepared by  
CONDENSED MATTER SCIENCES DIVISION  
OAK RIDGE NATIONAL LABORATORY  
Managed by  
UT- BATTELLE, LLC  
under  
Contract No. DE-AC05-00OR22725  
with the  
U.S. DEPARTMENT OF ENERGY  
Oak Ridge, Tennessee

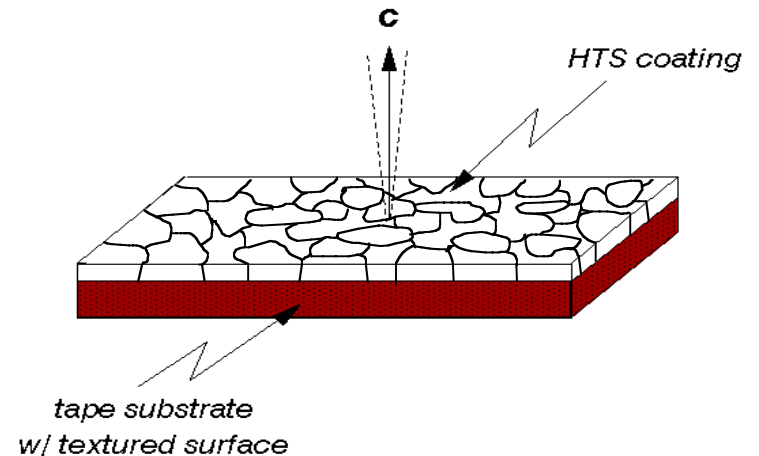
July, 03

# Vortices and Flux Pinning Coated Conductors

David Christen  
Oak Ridge National Lab

## Coated Conductors as imperfect films

- *epitaxial, c-axis growth from textured substrate surface*
- *~planar grain boundaries through entire thickness*
- *grain boundaries may limit critical currents*
- *Must be thick (for large currents)*

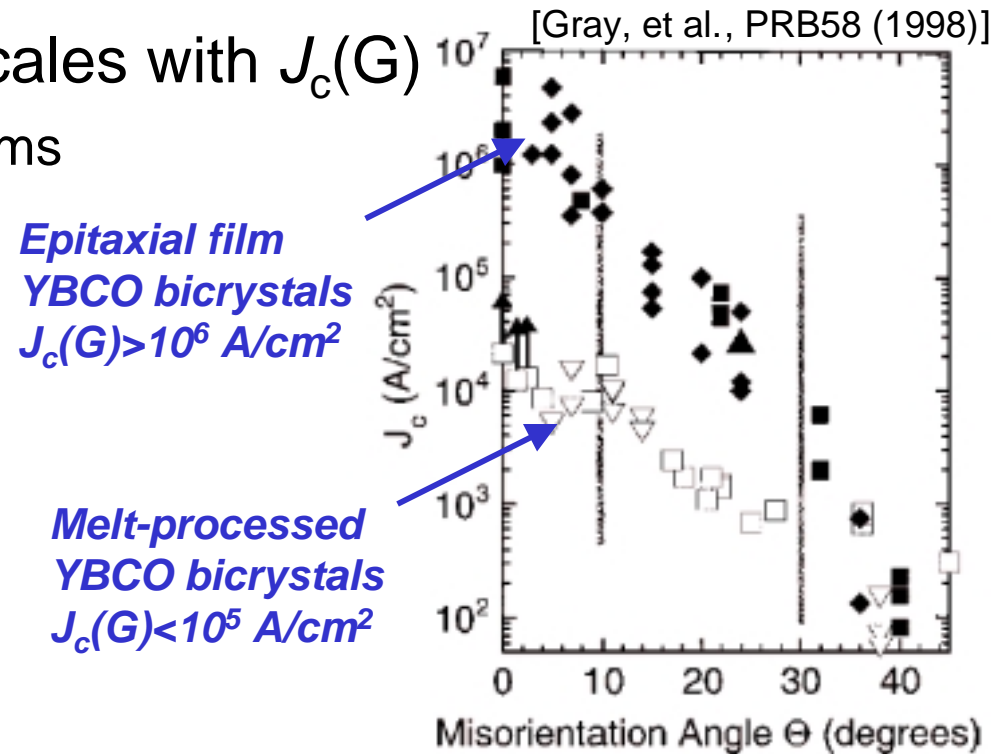
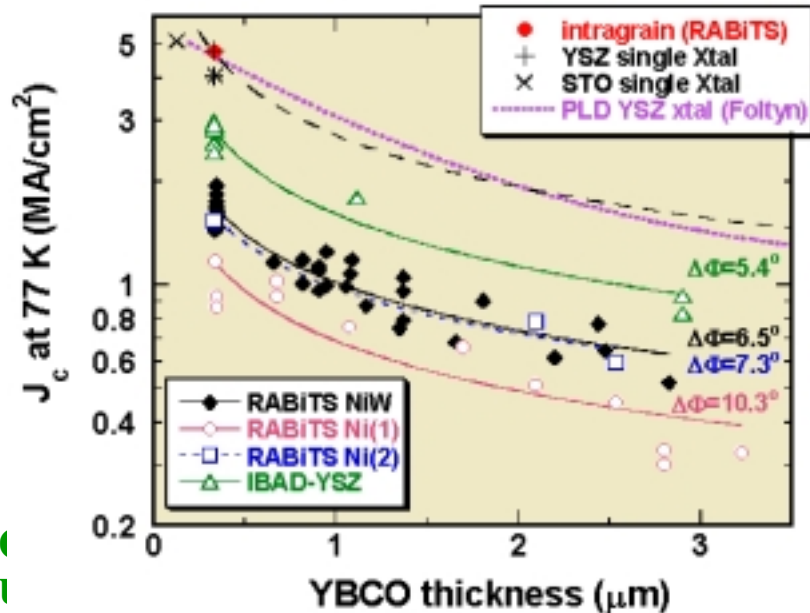


Why is it important to optimize flux pinning for intragrain  $J_c$ ?

# Why Flux Pinning in Coated Conductors?

For low-angle grain boundaries,

- Evidence suggests  $J_c(\text{GB})$  scales with  $J_c(\text{G})$ 
  - melt-processed vs epitaxial films
  - irradiated film bicrystals
    - $7^\circ$  GB dissipation decreases [Gurevich, et al. PRL 88 (2002)]
  - CC  $J_c(d)$  scales with texture

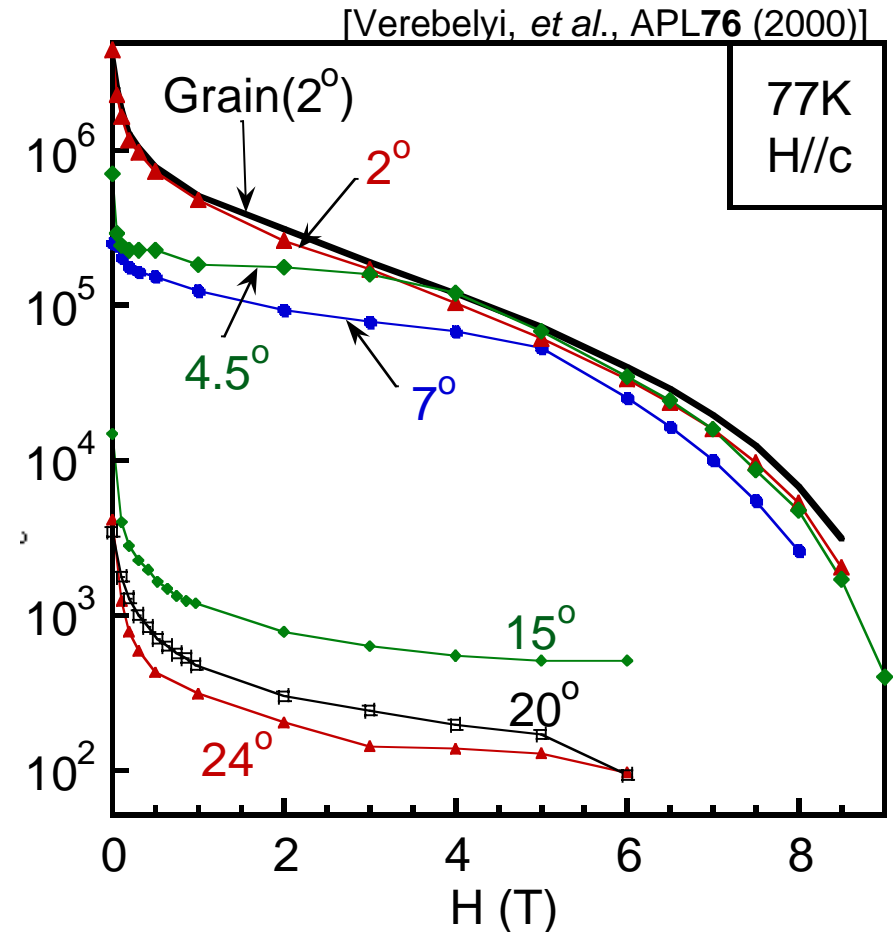
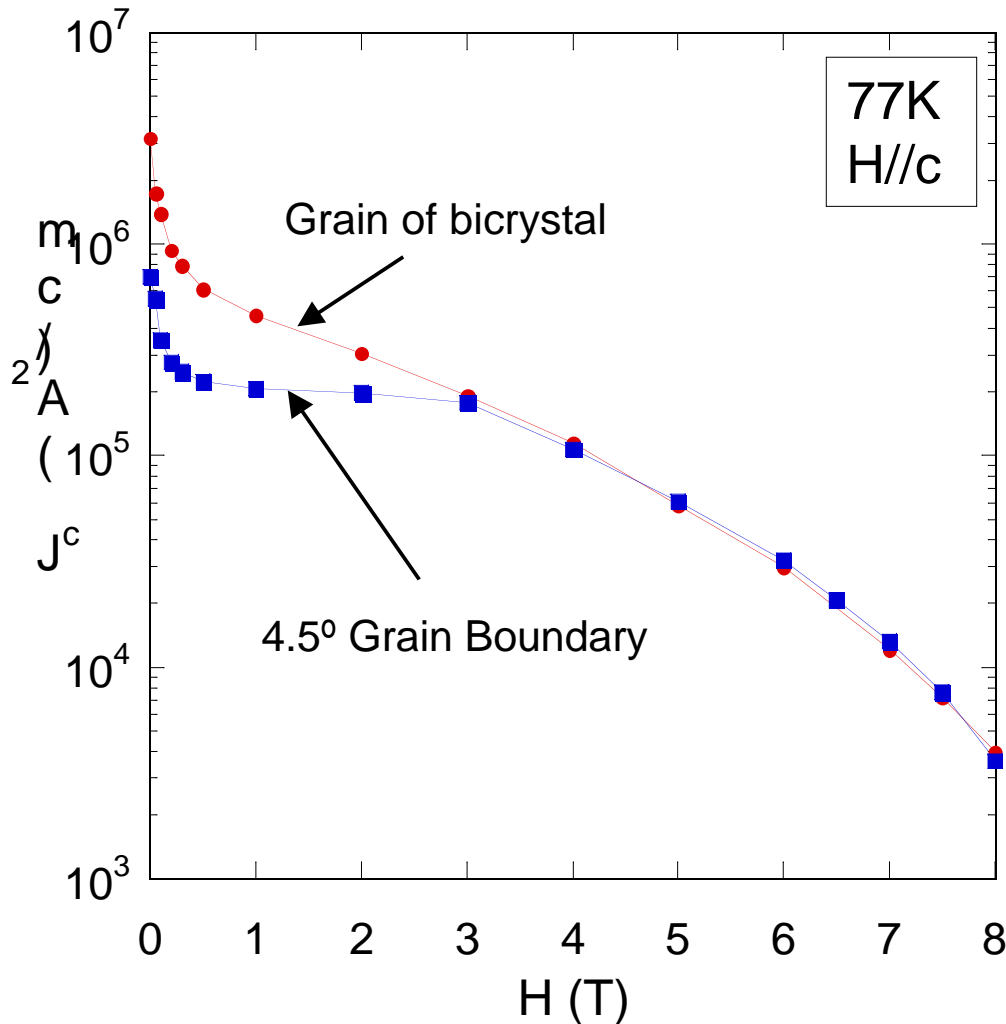


$J_c$  → Need optimal intragrain flux pinning for highest  $J_c(\text{GB})$

# Field Dependence of $J_c(\text{GB})$ and $J_c(\text{G})$

*For low-angle GB's:*

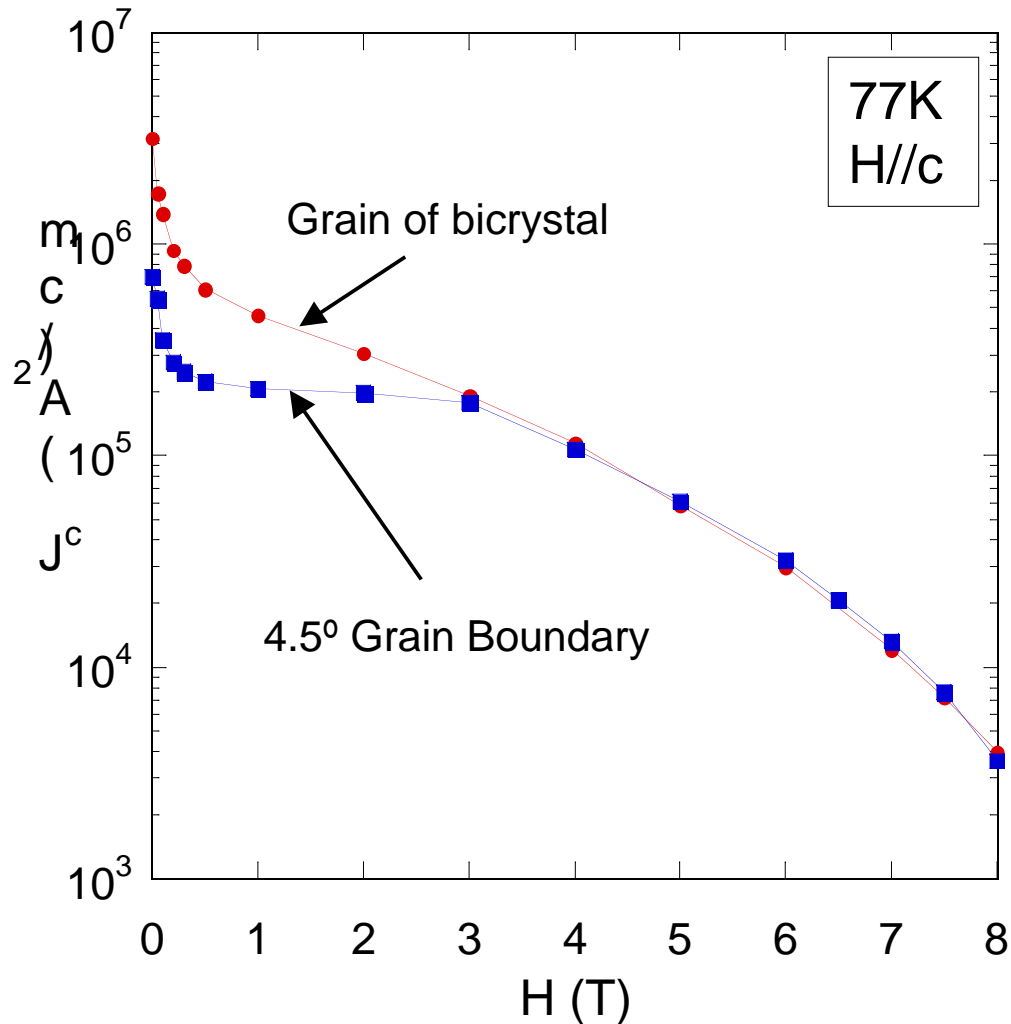
- $J_c$  limited by GB at low fields, but
- Grain dissipation dominates at high-field



# Field Dependence of $J_c(\text{GB})$ and $J_c(\text{G})$

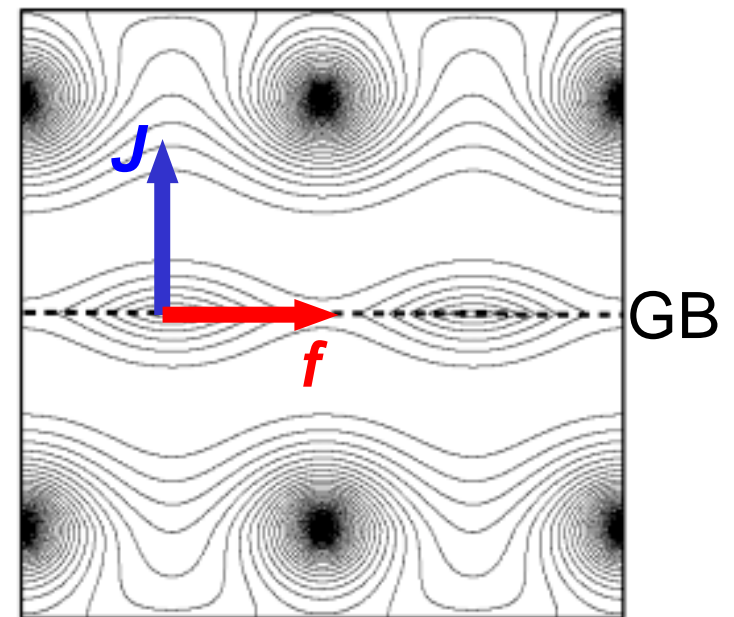
*For low-angle GB's:*

- $J_c$  limited by GB at low fields, but
- Grain dissipation dominates at high-field



**Consistent with model:**  
Pinning of GB vortices by pinned G vortices

[Gurevich, et al., PRL 88 (2002)]



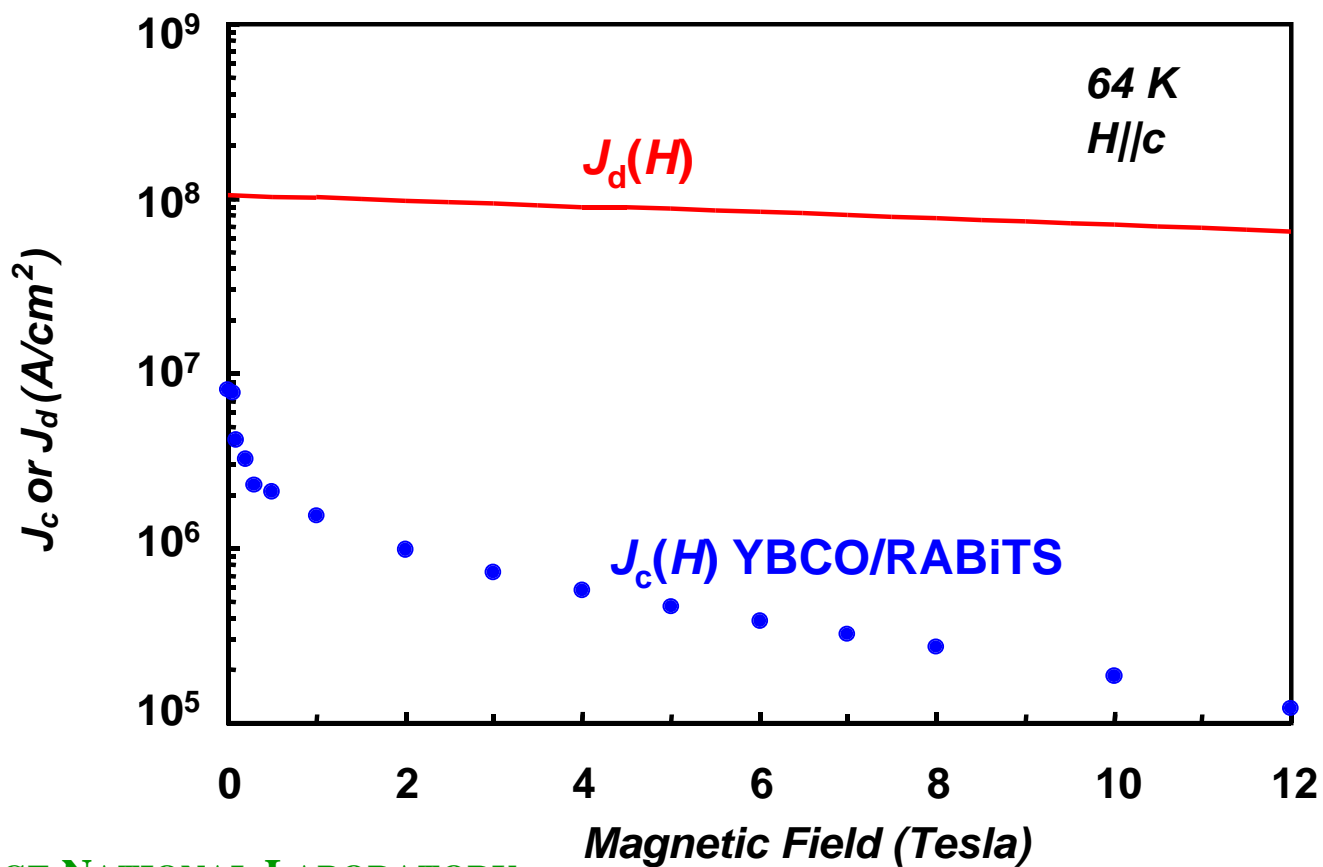
# Issues Affecting Intragrain Flux Pinning in Imperfect Films (Coated Conductors)

- **Intrinsic HTS material properties**
  - $T_c$
  - Anisotropy
  - Charge doping levels
- **Microstructure/ Defects**
  - **Compositional/Growth Effects**
    - growth on vicinal or rough substrate surfaces (dislocations, anti-phase boundaries)
    - twin boundaries, screw and edge dislocations and loops, phase segregation
  - **c-axis tilt grain boundaries**
    - Dislocation core pinning in low-angle limit
    - oxygen vacancies; cation disorder; isolated  $a\perp$ ; ...

# Flux-pinning in as-grown YBCO films is strong

- $J_c \sim 1/10 J_d$  in self-field, but
- far from optimal in field

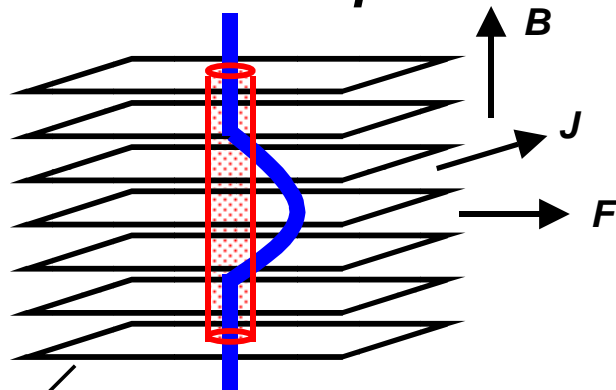
In principle,  $J_c \rightarrow J_d$  for pinning by matched columnar holes of radius  $\sim \sqrt{2} \xi$



# Thermally Activated Depinning from Columnar Defects

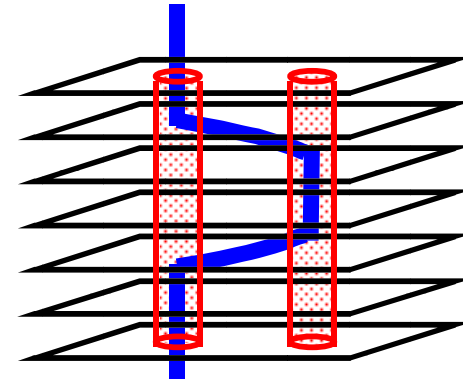
*Vortex density less than columnar defect density,  
depinning can occur by:*

**Vortex half-loop formation**



CuO<sub>2</sub> plane group

**double-kink formation**



## ENERGY CONSIDERATIONS

**Pinning line energy :  $u_p$**

**Vortex line tension:  $\tilde{\epsilon} = \epsilon \ell^2$**

**Anisotropy  $\gamma^2 = m_c/m_{ab}$  limits the depinning energy scale  $U_{\text{eff}} \propto (u_p \tilde{\epsilon})^{1/2}$**

**Depinning Probability**

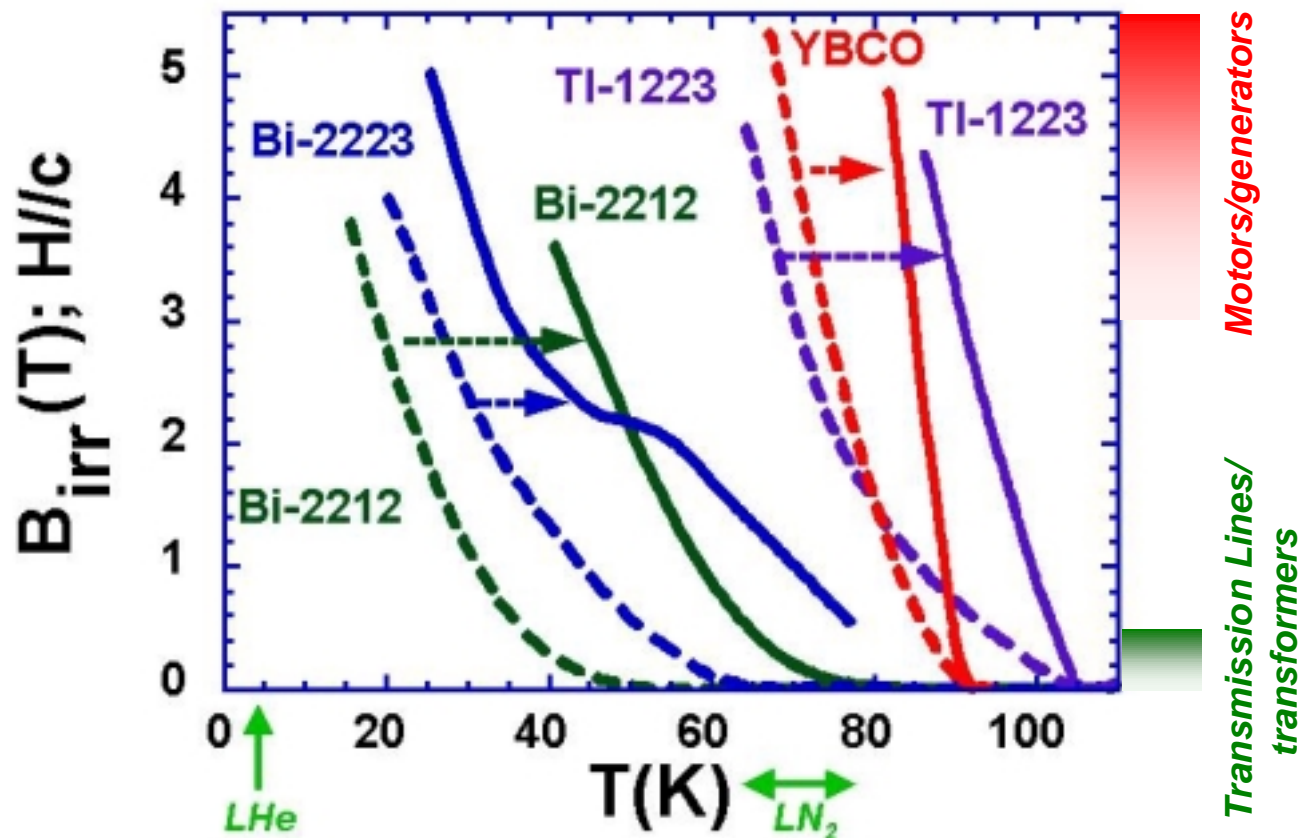
**OAK RIDGE NATIONAL LABORATORY**  $\exp[-U_{\text{eff}}/k_B T]$   
**U. S. DEPARTMENT OF ENERGY**





# Intrinsic Properties Define Limits of HTS Material Classes

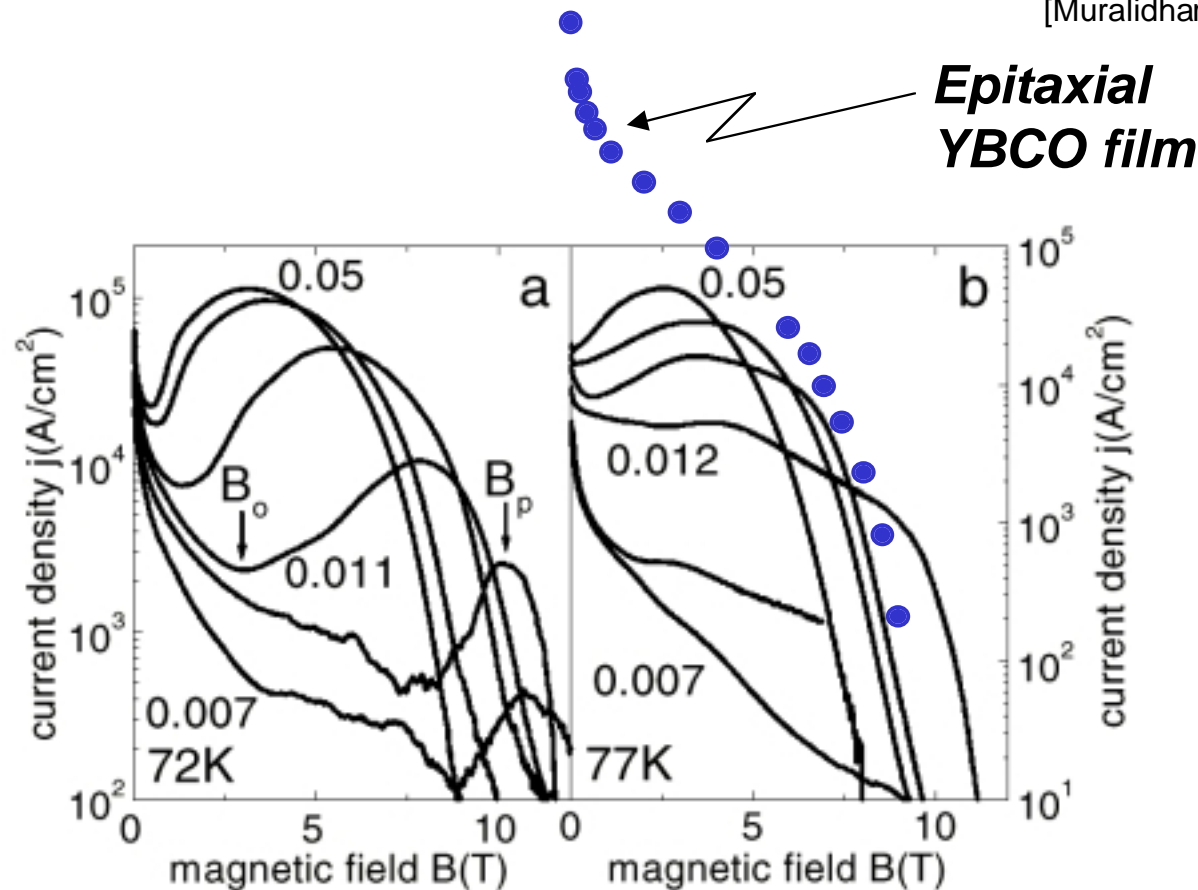
- For optimized flux pinning, the energy scale  $U_{\text{eff}} \propto (u_p \varepsilon)^{1/2} / \gamma$   
e.g.,  $\gamma \approx 5$  for YBCO,  $\gamma \approx 100$  for BSCCO
- Optimized pinning extends the operating range to higher  $H$ ,  $T$



# Flux pinning in as-grown YBCO films is strong

- Bulk, melt-processed crystals show “fishtail”  $J_c$  peak
- Epitaxial films show much stronger low-field  $J_c$
- High-field properties are similar (MPG crystals better?!)

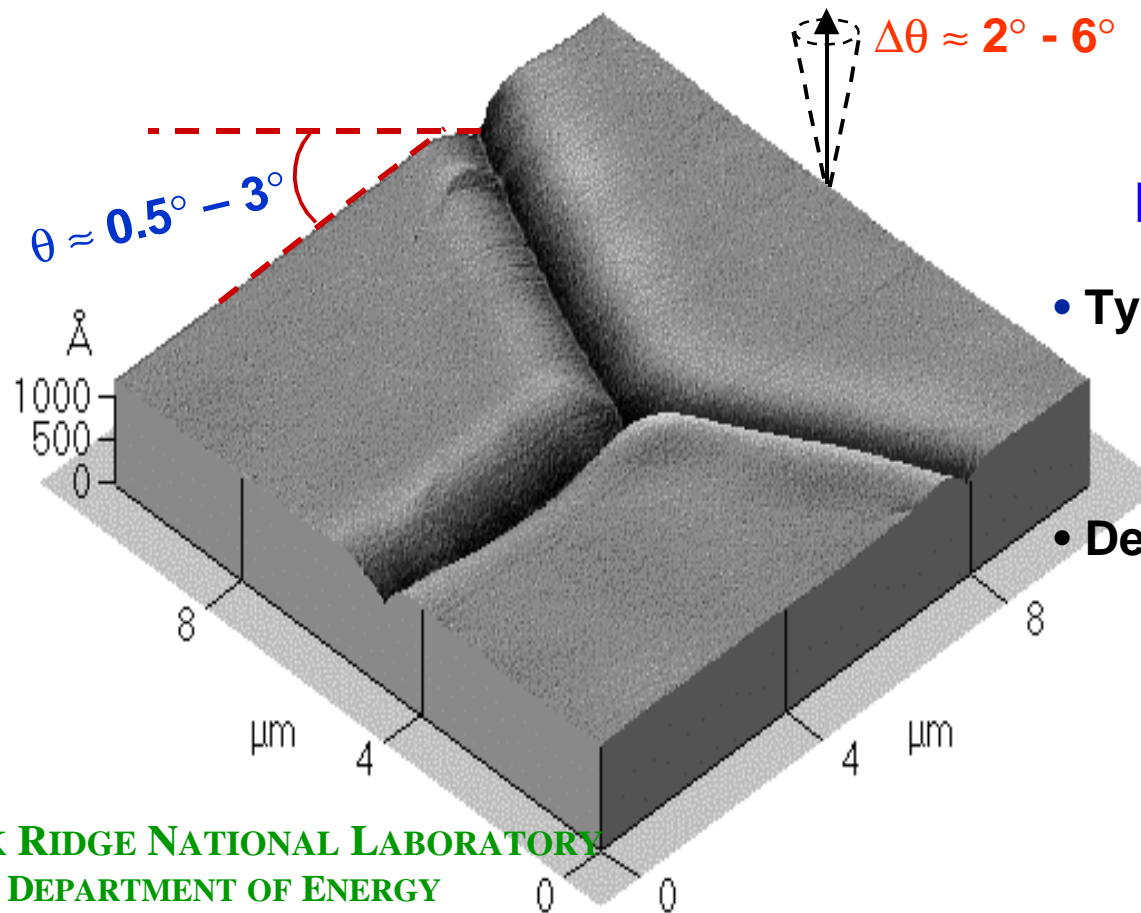
[Muralidhar, et al., APL 82 (2003)]



Kupfer, et al. IWCC (1999)

# Significance of Vicinal Substrate Surfaces in Coated Conductors

- **Coated conductor substrates have vicinal surfaces from:**
  - **Out-of-plane texture, typically  $2 - 6^\circ$ , of textured metal (RABiTS) or buffer layer (IBAD or ISD)**
  - **Thermal grain-boundary grooving of textured metal tape (RABiTS)**



**RABiTS Nickel  
processed at 800°C**

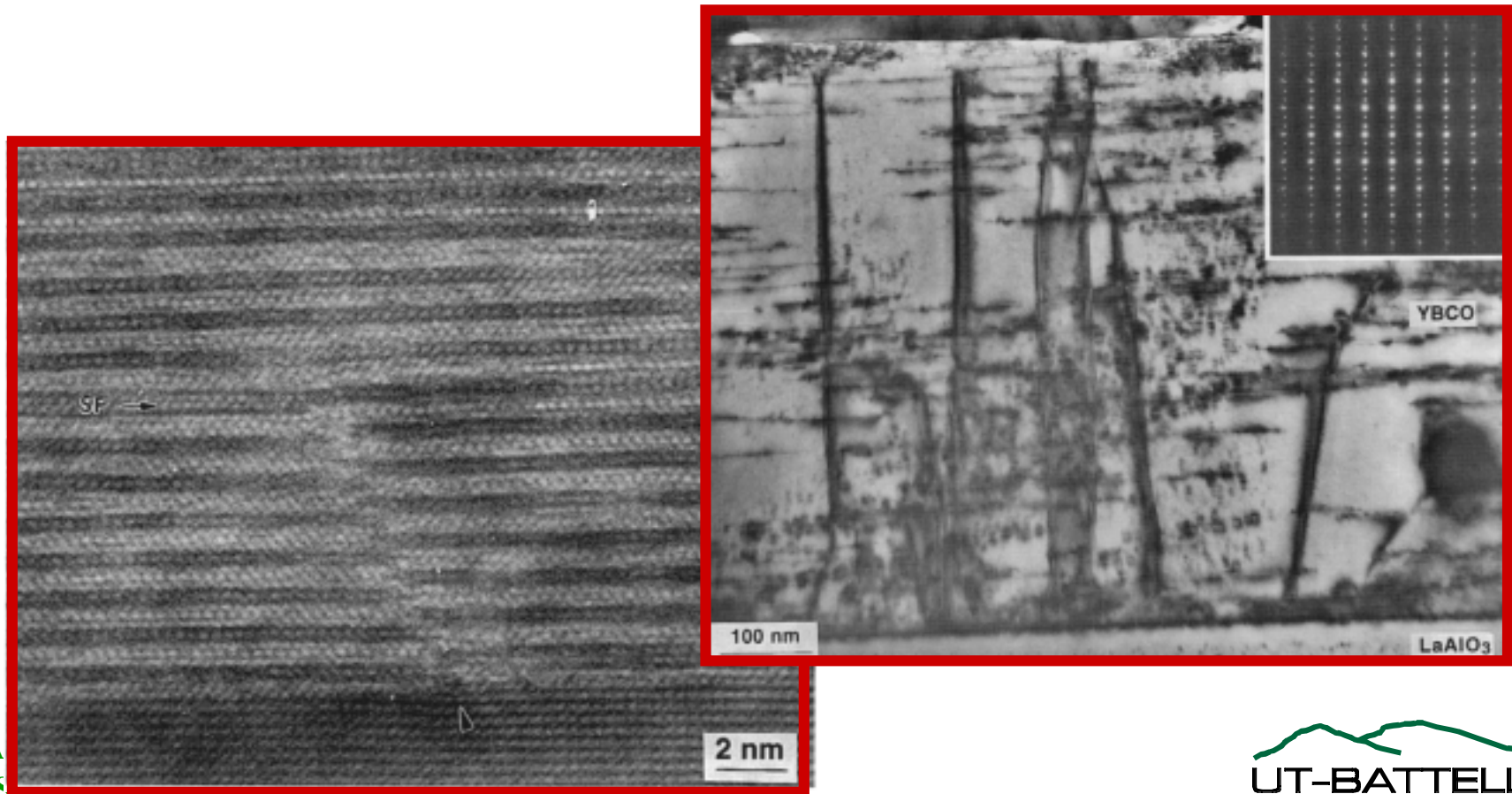
- **Typical groove dimensions:**
  - Width = 1.3-1.8  $\mu\text{m}$
  - Depth = 15 - 20 nm
- **Depth depends on g.b. angle and crystal plane**

# Origin of Pinning in Coated Conductors?

## Extended Defects from YBCO Growth on Vicinal Surfaces

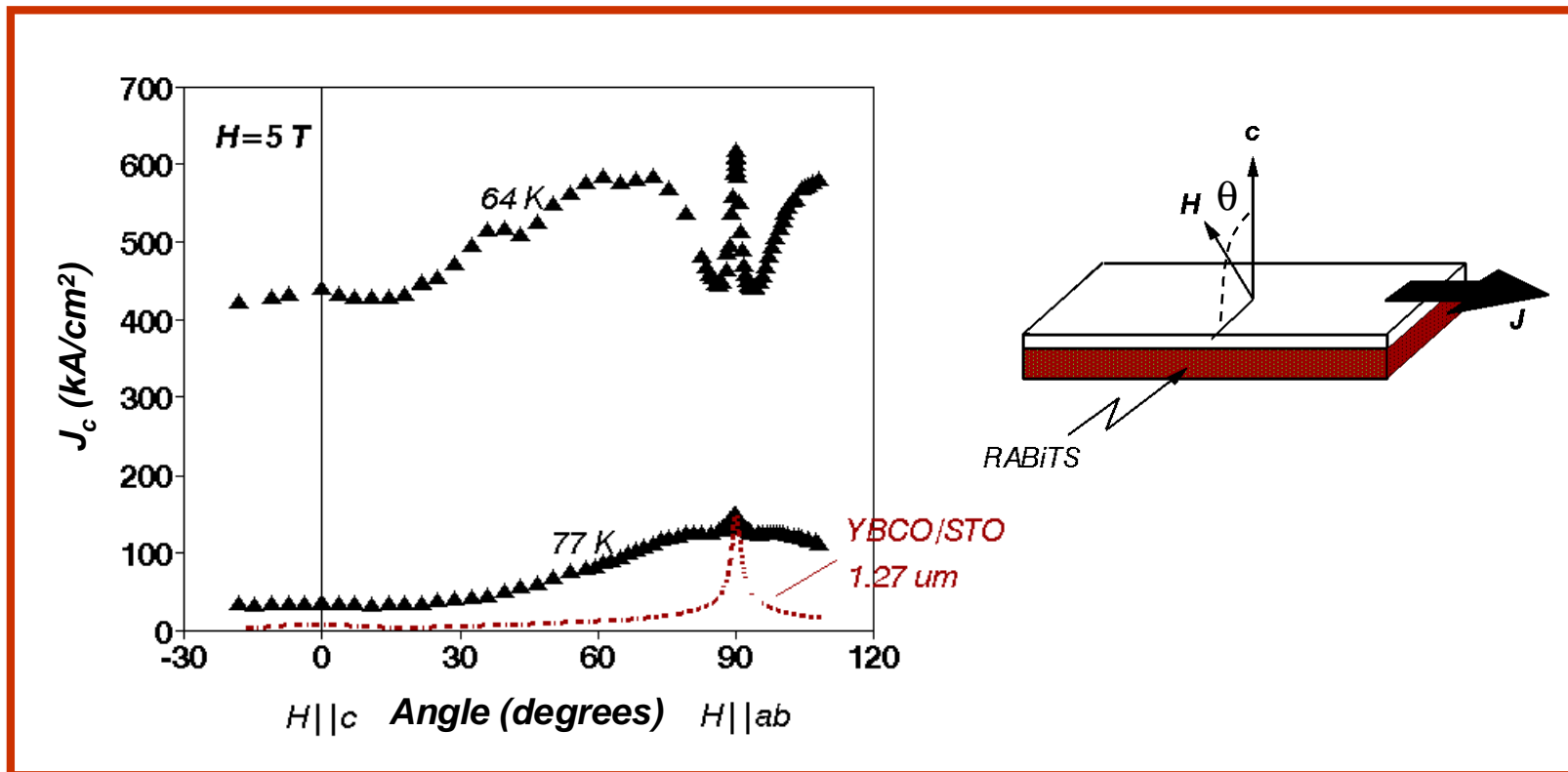
*c/3, anti-phase boundaries arise from YBCO growth on either side of substrate-surface step*

- *Localized strain, but defects can extend throughout film thickness*



# Anomalous Angular Dependence of $J_c$

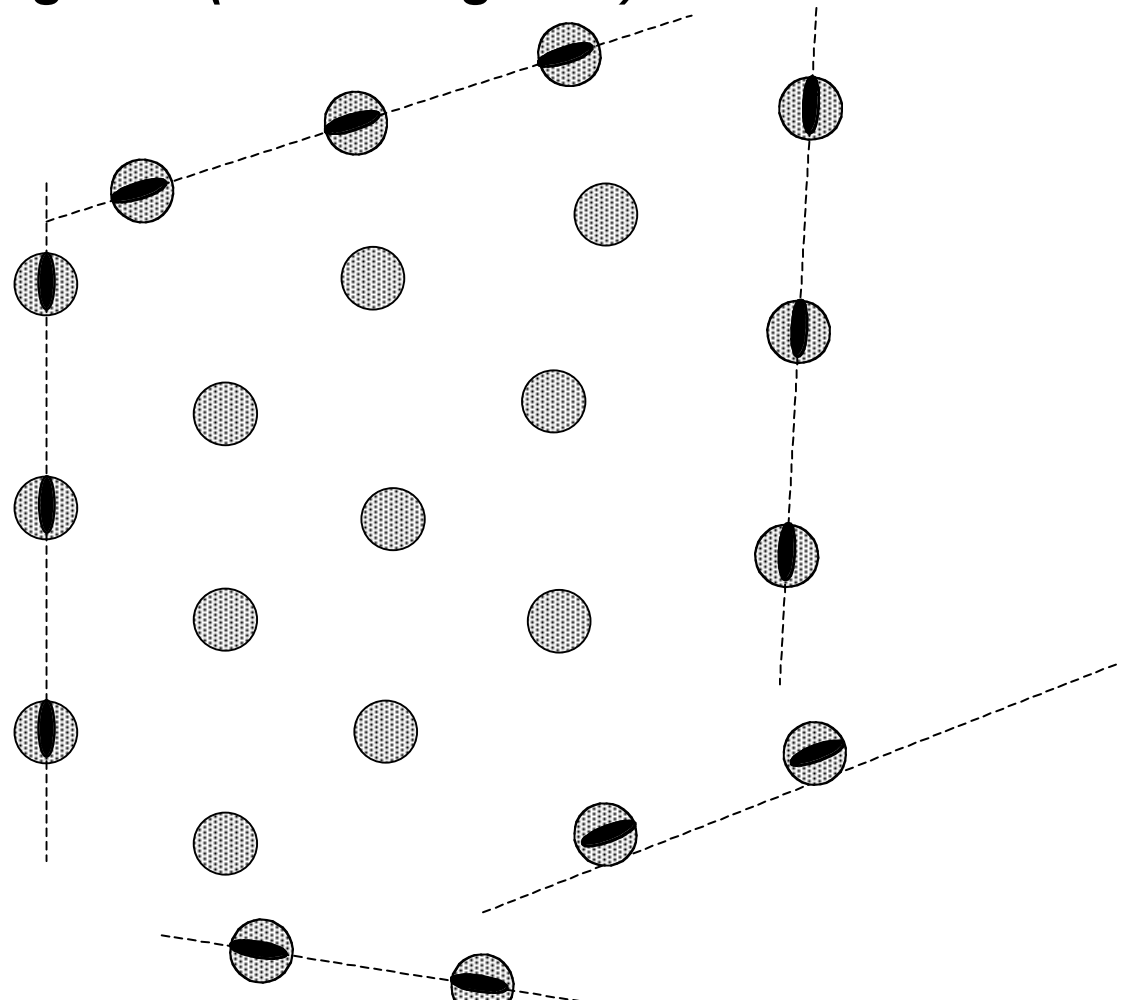
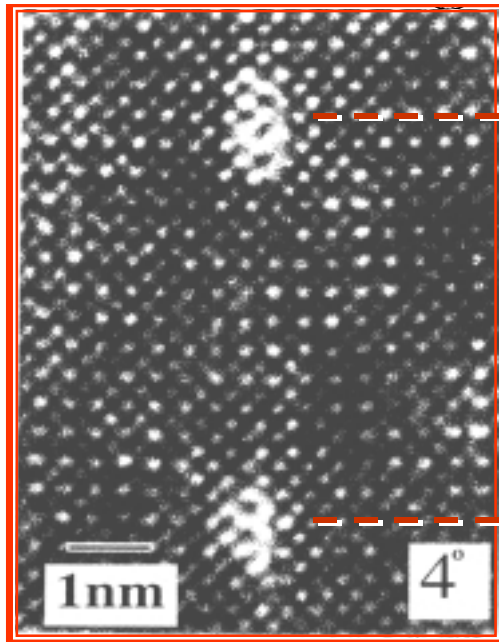
**YBCO/RABiTS, 0.6  $\mu\text{m}$  thick with  $J_c = 1.4 \text{ MA/cm}^2$**



# Possible Effects of Dislocation Cores in Low-Angle Boundaries

- The grain boundary becomes “invisible” for  $B > B_{core}$   
e.g. for  $\theta < 2^\circ$ ,  $GB B_{core} \lesssim 9$  Tesla
- The cores can act as additional, strong pinning defects  
“caging” of vortices within grains (for small grains)

Dislocations cores, ~5nm apart,  
according to  $2D\sin(\theta/2)=b$



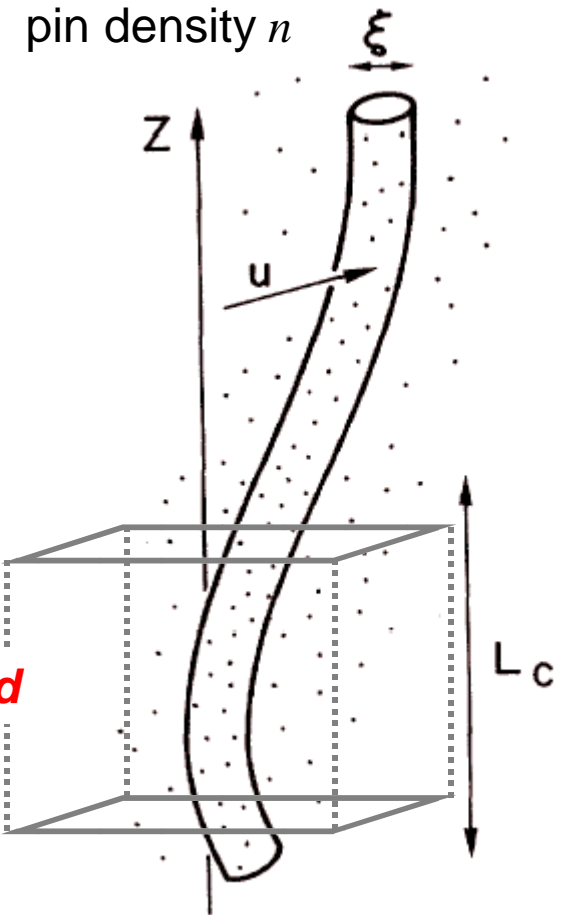
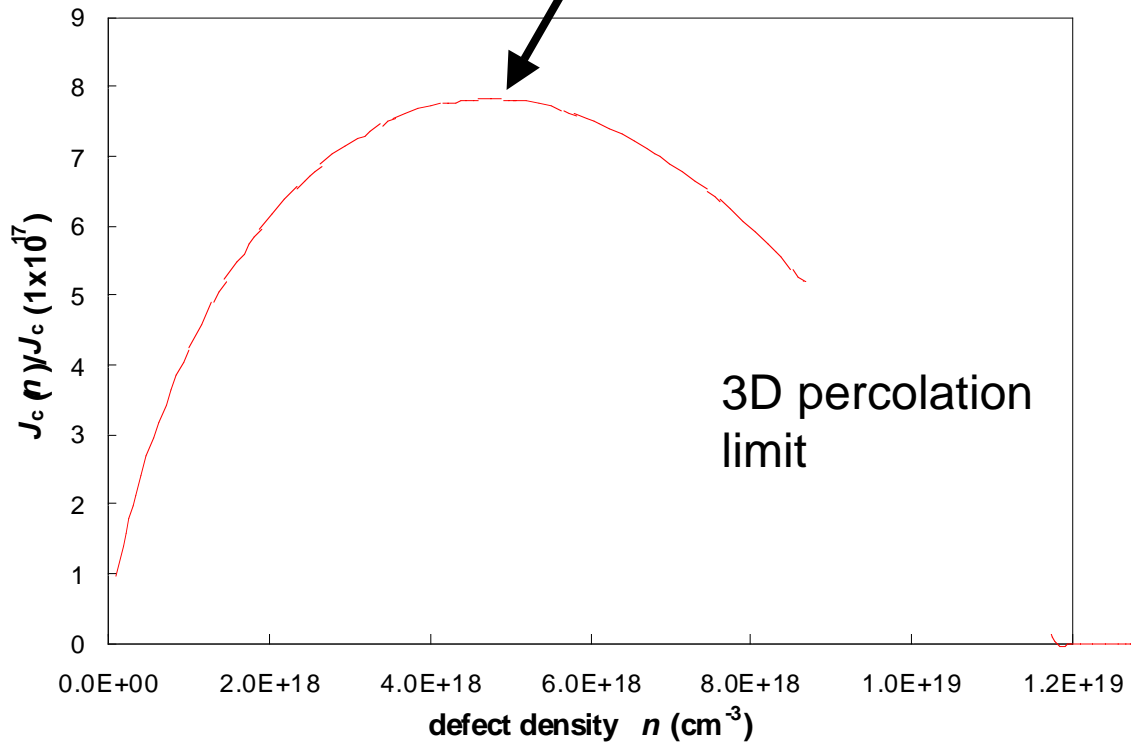
# Flux pinning by random, weak point-defects

Maximum  $J_c$ : collective pinning of single vortex

$$d^{1/2}$$

But, calculated  $L_c \sim 10 \text{ nm} \ll \text{CC thickness } d$

And, calculated max.  $J_c \sim 1\text{-}3 \text{ MA/cm}^2$



[Blatter, *et al.*, Rev. Mod. Phys **66** (1994)]

# Summary and Discussion Points

- ***GB's limit  $J_c$  at low fields, but benefit from intragrain flux pinning***
  - *Why are high-field properties limited by flux pinning?*
  - *Do the dislocation cores pin at high fields?*
  
- ***Extended or correlated defects should be important for intragrain flux pinning***
  - *Are they present in sufficient density?*
  - *What is their origin?*
  - *Can random point pins account for observed  $J_c$ 's?*
  - *...*